1.   A method of rendering a three-dimensional model,

comprising:

obtaining a characteristic of the three-dimensional model;

determining a three-dimensional dither pattern based on

5   the characteristic; and

rendering the three-dimensional model using the three-

dimensional dither pattern.

2.   The method of claim 1, wherein determining comprises

10   selecting a number of points to make up the three-dimensional

dither pattern and a location of the points on the three-

dimensional model.

3.   The method of claim 1, wherein the characteristic is

15   obtained for a region of the three-dimensional model, and the

three-dimensional dither pattern is determined for the region.

4.   The method of claim 3, wherein characteristics are

obtained for different regions of the three-dimensional model,

20   different three-dimensional dither patterns are determined for

the different regions based on the characteristics for the

different regions, and the three-dimensional model is rendered

using the different three-dimensional dither patterns.

5.   The method of claim 1, wherein the three-dimensional dither pattern comprises data specifying pixels to illuminate when rendering the three-dimensional model.

6.   The method of claim 5, wherein the pixels define individual points in the three-dimensional dither pattern.

7.   The method of claim 1, wherein the characteristic comprises a density of the three-dimensional model.

8.   The method of claim 7, wherein the density is obtained for a three-dimensional region of the three-dimensional model by averaging densities of sub-regions within the three-dimensional region.

9.   The method of claim 1, wherein the characteristic comprises one of a color of the three-dimensional model, a field strength in the three-dimensional model, a temperature in the three-dimensional model, and a pollution concentration in the three-dimensional model.

10. The method of claim 1, wherein determining the three-dimensional dither pattern comprises selecting the three-dimensional dither pattern from a number of three-dimensional dither patterns stored in memory.

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11. An article comprising a machine-readable medium that stores executable instructions for rendering a three-dimensional model, the instructions causing a machine to:

obtain a characteristic of the three-dimensional model;

10   determine a three-dimensional dither pattern based on the characteristic; and

render the three-dimensional model using the three-dimensional dither pattern.

15   12. The article of claim 11, wherein determining comprises selecting a number of points to make up the three-dimensional dither pattern and a location of the points on the three-dimensional model.

20   13. The article of claim 11, wherein the characteristic is obtained for a region of the three-dimensional model, and the three-dimensional dither pattern is determined for the region.

14.   The article of claim 13, wherein characteristics are obtained for different regions of the three-dimensional model, different three-dimensional dither patterns are determined for the different regions based on the characteristics for the different regions, and the three-dimensional model is rendered using the different three-dimensional dither patterns.

15.   The article of claim 11, wherein the three-dimensional dither pattern comprises data specifying pixels to illuminate when rendering the three-dimensional model.

16.   The article of claim 15, wherein the pixels define individual points in the three-dimensional dither pattern.

17.   The article of claim 11, wherein the characteristic comprises a density of the three-dimensional model.

18.   The article of claim 17, wherein the density is obtained for a three-dimensional region of the three-dimensional model by averaging densities of sub-regions within the three-dimensional region.

19. The article of claim 11, wherein the characteristic comprises one of a color of the three-dimensional model, a field strength in the three-dimensional model, a temperature in the three-dimensional model, and a pollution concentration in the three-dimensional model.

20. The article of claim 11, wherein determining the three-dimensional dither pattern comprises selecting the three-dimensional dither pattern from a number of three-dimensional dither patterns stored in memory.

21. An apparatus for rendering a three-dimensional model, comprising:

a memory that stores executable instructions; and

a processor that executes the instructions to:

obtain a characteristic of the three-dimensional model;

determine a three-dimensional dither pattern based on the characteristic; and

render the three-dimensional model using the three-dimensional dither pattern.

22.   The apparatus of claim 21, wherein determining comprises selecting a number of points to make up the three-dimensional dither pattern and a location of the points on the three-dimensional model.

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23.   The apparatus of claim 21, wherein the characteristic is obtained for a region of the three-dimensional model, and the three-dimensional dither pattern is determined for the region.

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24.   The apparatus of claim 23, wherein characteristics are obtained for different regions of the three-dimensional model, different three-dimensional dither patterns are determined for the different regions based on the characteristics for the different regions, and the three-dimensional model is rendered using the different three-dimensional dither patterns.

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25.   The apparatus of claim 21, wherein the three-dimensional dither pattern comprises data specifying pixels to illuminate when rendering the three-dimensional model.

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26.   The apparatus of claim 25, wherein the pixels define individual points in the three-dimensional dither pattern.

27.   The apparatus of claim 21, wherein the
5   characteristic comprises a density of the three-dimensional model.

28.   The apparatus of claim 27, wherein the density is obtained for a three-dimensional region of the three-
10   dimensional model by averaging densities of sub-regions within the three-dimensional region.

29.   The apparatus of claim 21, wherein the characteristic comprises one of a color of the three-
15   dimensional model, a field strength in the three-dimensional model, a temperature in the three-dimensional model, and a pollution concentration in the three-dimensional model.

30.   The apparatus of claim 21, wherein determining the
20   three-dimensional dither pattern comprises selecting the three-dimensional dither pattern from a number of three-dimensional dither patterns stored in memory.